


<b>Search Notes</b> 	<b>Application/Control No.</b> 10565406	<b>Applicant(s)/Patent Under Reexamination</b> BAIK ET AL.
	<b>Examiner</b> Lorna M Douyon	<b>Art Unit</b> 1796

SEARCHED			
Class	Subclass	Date	Examiner
510	443, 452, 509, 511		LMD

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	9/24/08	LMD

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/Lorna M Douyon/ Primary Examiner, Art Unit 1796
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